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Vladimir Segal et al.FILING DATE
February 13, 2001GROUP
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U.S. PATENT DOCUMENTS

Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
AW	AA	5,590,389	12/96	Dunlop et al.			
AW	AB	5,513,512	05/96	Segal			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
AW	AM	WO 98/24945	6/11/98	PCT				
AW	AN	WO 01/29279 A1	4/26/01	PCT				
AW	AO	07286268	10/31/95	Japan (abstract only)				
	AP							
	AQ							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AW	AR		Haupt et al., "Drift in film thickness uniformity arising from sputtering target recrystallization". J. Vac. Sci. Technol. A 7(3), May/Jun 1989, pp. 2355-2358.
AW	AS		Ferrasse et al., "Development of a submicrometer-grained microstructure in aluminum 6061 using equal channel angular extrusion". J. Mater. Res. Vol. 12, No. 5, May 1997, pp. 1253-1261.
	AT		

EXAMINER

AW

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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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